FAIRCHILD SEMICONDUCTOR®

July 2010

FDME1034CZT

Complementary PowerTrench® MOSFET

N-channel: 20 V, 3.8 A, 66 mΩ P-channel: -20 V, -2.6 A, 142 mΩ

Features

Q1: N-Channel

- Max $r_{DS(on)}$ = 66 mΩ at V_{GS} = 4.5 V, I_D = 3.4 A
- Max $r_{DS(on)}$ = 86 mΩ at V_{GS} = 2.5 V, I_D = 2.9 A
- Max $r_{DS(on)}$ = 113 mΩ at V_{GS} = 1.8 V, I_D = 2.5 A
- Max $r_{DS(on)}$ = 160 mΩ at V_{GS} = 1.5 V, I_D = 2.1 A

Q2: P-Channel

- Max $r_{DS(on)}$ = 142 mΩ at V_{GS} = -4.5 V, I_D = -2.3 A
- Max $r_{DS(on)}$ = 213 mΩ at V_{GS} = -2.5 V, I_D = -1.8 A
- Max $r_{DS(on)}$ = 331 mΩ at V_{GS} = -1.8 V, I_D = -1.5 A
- Max $r_{DS(on)}$ = 530 mΩ at V_{GS} = -1.5 V, I_D = -1.2 A

- Low profile: 0.55 mm maximum in the new package MicroFET 1.6x1.6 **Thin**
- Free from halogenated compounds and antimony oxides
- HBM ESD protection level > 1600 V (Note 3)
- RoHS Compliant

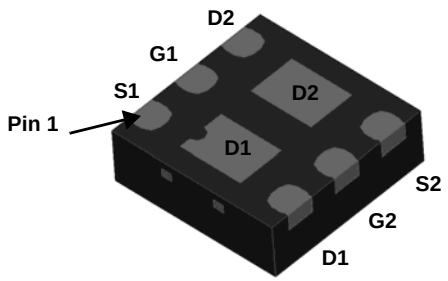
General Description

This device is designed specifically as a single package solution for a DC/DC 'Switching' MOSFET in cellular handset and other ultra-portable applications. It features an independent N-Channel & P-Channel MOSFET with low on-state resistance for minimum conduction losses. The gate charge of each MOSFET is also minimized to allow high frequency switching directly from the controlling device.

The MicroFET 1.6x1.6 **Thin** package offers exceptional thermal performance for it's physical size and is well suited to switching and linear mode applications.

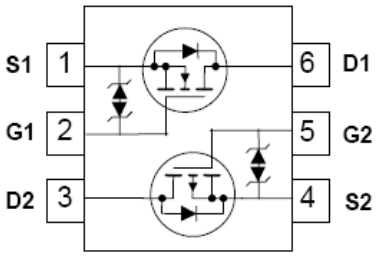
Applications

- DC-DC Conversion
- Level Shifted Load Switch



BOTTOM

TOP



MicroFET 1.6x1.6 Thin

MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter			Q1	Q2	Units
V_{DS}	Drain to Source Voltage			20	-20	V
V_{GS}	Gate to Source Voltage			±8	±8	V
I_D	Drain Current -Continuous	T_A = 25 °C	(Note 1a)	3.8	-2.6	A
	-Pulsed			6	-6	
P_D	Power Dissipation for Single Operation	T_A = 25 °C	(Note 1a)	1.4		W
	Power Dissipation for Single Operation	T_A = 25 °C	(Note 1b)	0.6		
T_J, T_{STG}	Operating and Storage Junction Temperature Range			-55 to +150		°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Single Operation)	(Note 1a)	90	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Single Operation)	(Note 1b)	195	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
5T	FDME1034CZT	MicroFET 1.6x1.6 **Thin**	7 ”	8 mm	5000 units

Electrical Characteristics T_J = 25 °C unless otherwise noted

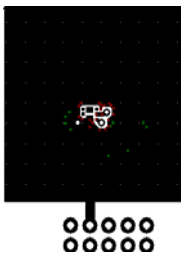
Symbol	Parameter	Test Conditions	Type	Min	Typ	Max	Units
Off Characteristics							
BV_{DSS}	Drain to Source Breakdown Voltage	I_D = 250 μA, V_{GS} = 0 V I_D = -250 μA, V_{GS} = 0 V	Q1 Q2	20 -20			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C I_D = -250 μA, referenced to 25 °C	Q1 Q2		16 -12		mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 16 V, V_{GS} = 0 V V_{DS} = -16 V, V_{GS} = 0 V	Q1 Q2			1 -1	μA
I_{GSS}	Gate to Source Leakage Current	V_{GS} = ±8 V, V_{DS} = 0 V	All			±10	μA
On Characteristics							
$V_{GS(th)}$	Gate to Source Threshold Voltage	V_{GS} = V_{DS}, I_D = 250 μA V_{GS} = V_{DS}, I_D = -250 μA	Q1 Q2	0.4 -0.4	0.7 -0.6	1.0 -1.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C	Q1 Q2		-3 2		mV/°C
$r_{DS(on)}$	Drain to Source On Resistance	V_{GS} = 4.5 V, I_D = 3.4 A	Q1		55	66	mΩ
		V_{GS} = 2.5 V, I_D = 2.9 A			68	86	
		V_{GS} = 1.8 V, I_D = 2.5 A			85	113	
		V_{GS} = 1.5 V, I_D = 2.1 A			106	160	
		V_{GS} = 4.5 V, I_D = 3.4 A, T_J =125°C			76	112	
		V_{GS} = -4.5 V, I_D = -2.3 A	Q2		95	142	
		V_{GS} = -2.5 V, I_D = -1.8 A			120	213	
		V_{GS} = -1.8 V, I_D = -1.5 A			150	331	
		V_{GS} = -1.5 V, I_D = -1.2 A			190	530	
		V_{GS} = -4.5 V, I_D = -2.3 A , T_J = 125 °C			128	190	
g_{FS}	Forward Transconductance	V_{DS} = 4.5 V, I_D =3.4 A V_{DS} = -4.5 V, I_D = -2.3 A	Q1 Q2		9 7		S
Dynamic Characteristics							
C_{iss}	Input Capacitance	Q1 V_{DS} = 10 V, V_{GS} = 0 V, f = 1 MHz Q2 V_{DS} = -10 V, V_{GS} = 0 V, f = 1 MHz	Q1 Q2		225 305	300 405	pF
C_{oss}	Output Capacitance		Q1 Q2		40 55	55 75	pF
C_{rss}	Reverse Transfer Capacitance		Q1 Q2		25 50	40 75	pF
Switching Characteristics							
$t_{d(on)}$	Turn-On Delay Time	Q1 V_{DD} = 10 V, I_D = 1 A, V_{GS} = 4.5 V, R_{GEN} = 6 Ω Q2 V_{DD} = -10 V, I_D = -1 A, V_{GS} = -4.5 V, R_{GEN} = 6 Ω	Q1 Q2		4.5 4.7	10 10	ns
t_r	Rise Time		Q1 Q2		2.0 4.8	10 10	
$t_{d(off)}$	Turn-Off Delay Time		Q1 Q2		15 33	27 53	
t_f	Fall Time		Q1 Q2		1.7 16	10 29	
Q_g	Total Gate Charge	Q1 V_{DD} = 10 V, I_D = 3.4 A, V_{GS} = 4.5 V Q2 V_{DD} = -10 V, I_D = -2.3 A, V_{GS} = -4.5 V	Q1 Q2		3 5.5	4.2 7.7	nC
Q_{gs}	Gate to Source Gate Charge		Q1 Q2		0.4 0.6		
Q_{gd}	Gate to Drain “Miller” Charge		Q1 Q2		0.6 1.4		

Electrical Characteristics T_J = 25 °C unless otherwise noted

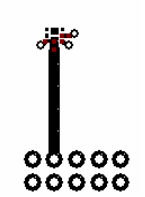
Symbol	Parameter	Test Conditions	Type	Min	Typ	Max	Units
Drain-Source Diode Characteristics							
V_{SD}	Source to Drain Diode Forward Voltage	V_{GS} = 0 V, I_S = 0.9 A (Note 2) V_{GS} = 0 V, I_S = -0.9 A (Note 2)	Q1 Q2		0.7 -0.8	1.2 -1.2	V
t_{rr}	Reverse Recovery Time	Q1 I_F = 3.4 A, di/dt = 100 A/μS	Q1 Q2		8.5 16	17 29	ns
Q_{rr}	Reverse Recovery Time	Q2 I_F = -2.3 A, di/dt = 100 A/μs	Q1 Q2		1.4 4.4	10 10	nC

Notes:

1. $R_{\theta JA}$ is determined with the device mounted on a 1 in^2 pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a. 90 °C/W when mounted on a 1 in^2 pad of 2 oz copper.



b. 195 °C/W when mounted on a minimum pad of 2 oz copper.

2. Pulse Test: Pulse Width < 300 μs, Duty cycle < 2.0%.

3. The diode connected between the gate and source serves only as protection ESD. No gate overvoltage rating is implied.

Typical Characteristics (Q1 N-Channel) T_J = 25°C unless otherwise noted

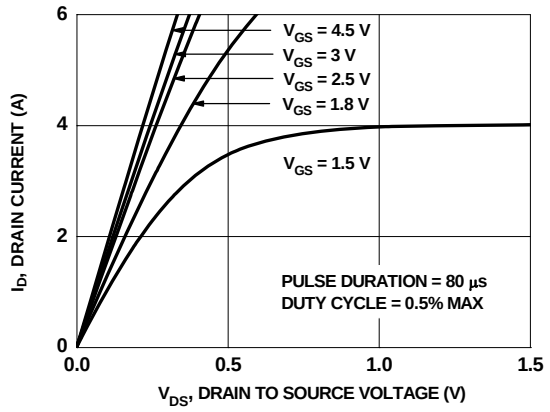


Figure 1. On Region Characteristics

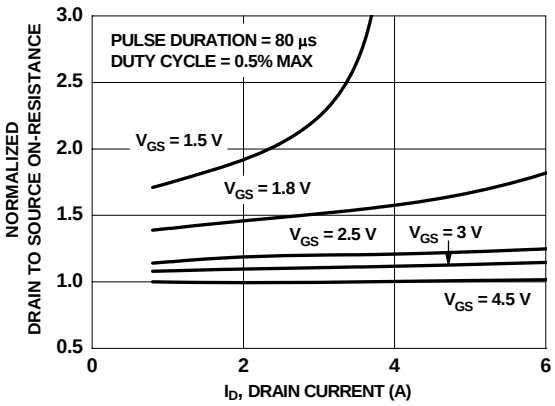


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

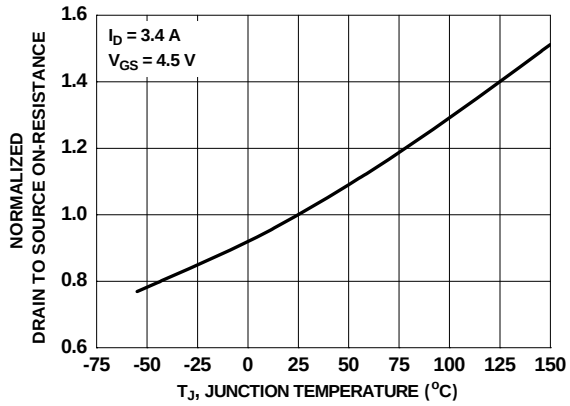


Figure 3. Normalized On Resistance vs Junction Temperature

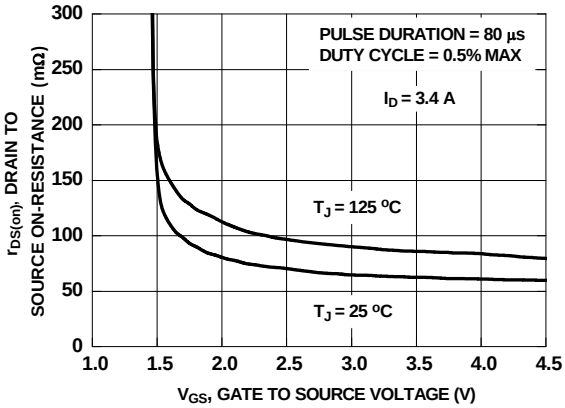


Figure 4. On-Resistance vs Gate to Source Voltage

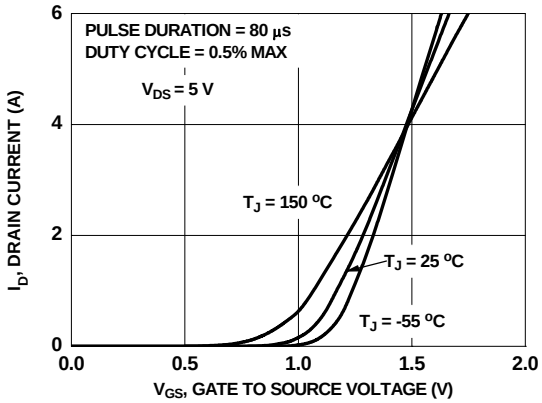


Figure 5. Transfer Characteristics

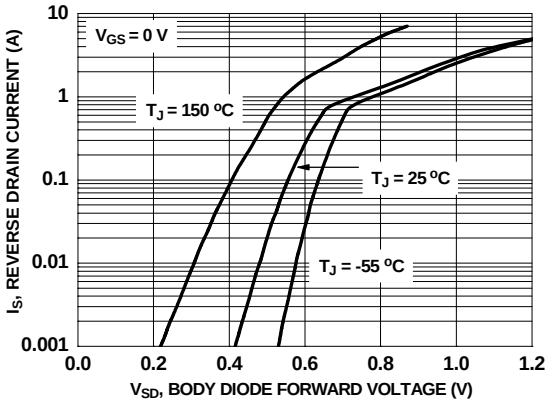


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics (Q1 N-Channel) T_J = 25°C unless otherwise noted

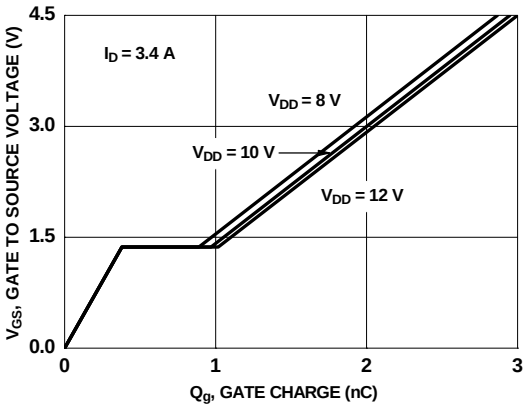


Figure 7. Gate Charge Characteristics

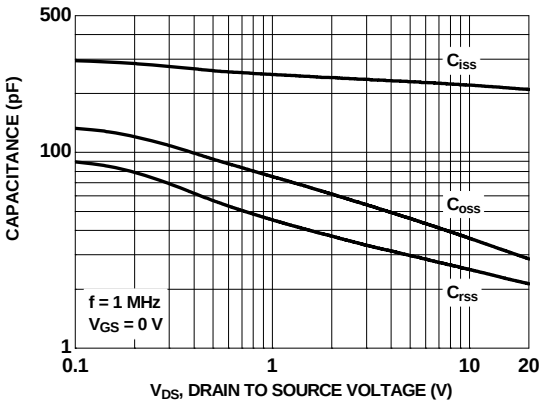


Figure 8. Capacitance vs Drain to Source Voltage

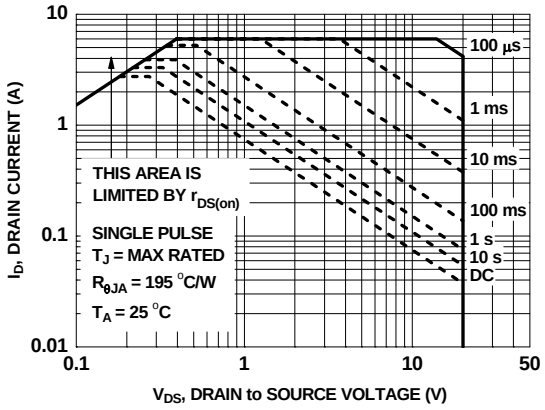


Figure 9. Forward Bias Safe Operating Area

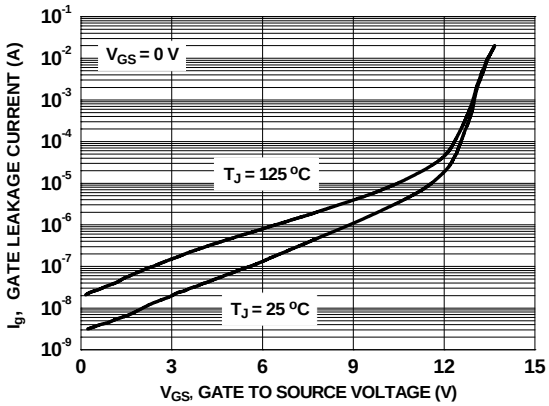


Figure 10. Gate Leakage Current vs Gate to Source Voltage

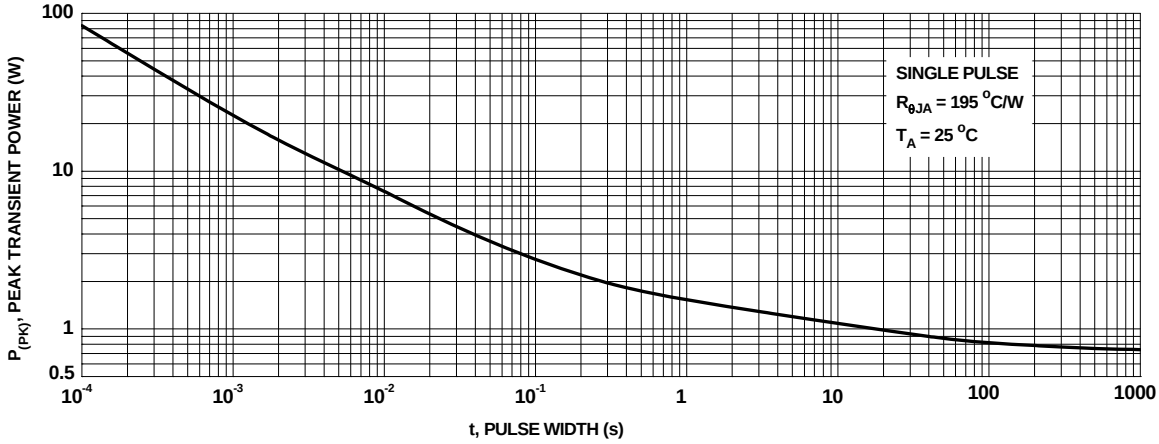


Figure 11. Single Pulse Maximum Power Dissipation

Typical Characteristics (Q1 N-Channel) T_J = 25°C unless otherwise noted

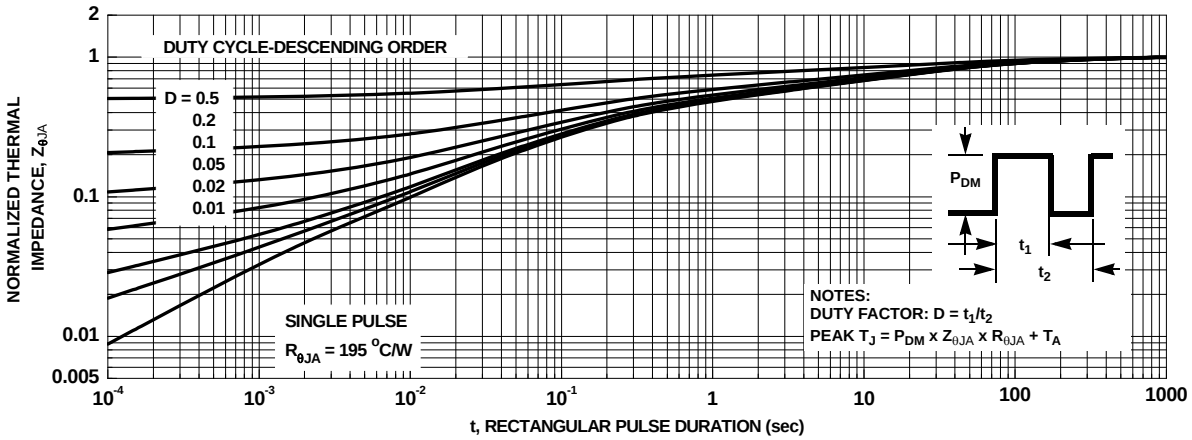


Figure 12. Junction-to-Ambient Transient Thermal Response Curve

Typical Characteristics (Q2 P-Channel) T_J = 25 °C unless otherwise noted

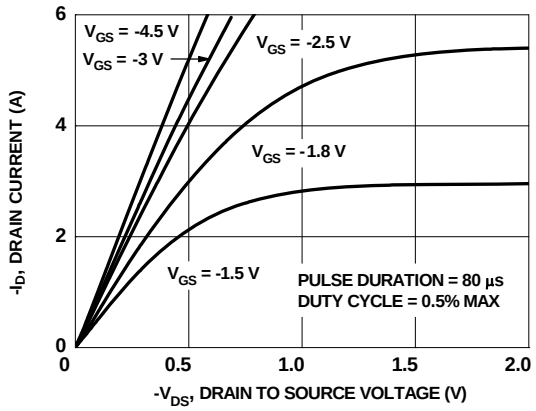


Figure 13. On- Region Characteristics

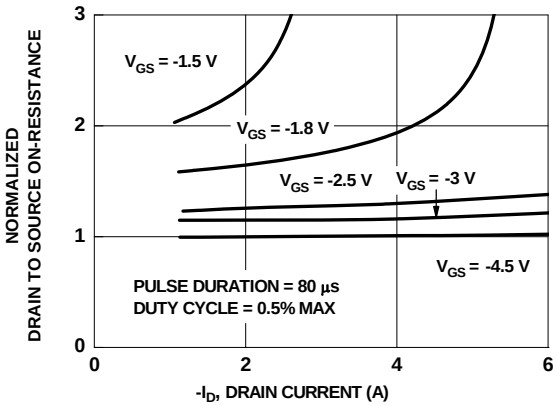


Figure 14. Normalized on-Resistance vs Drain Current and Gate Voltage

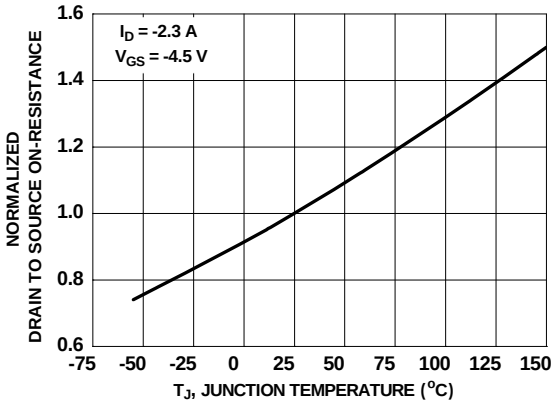


Figure 15. Normalized On-Resistance vs Junction Temperature

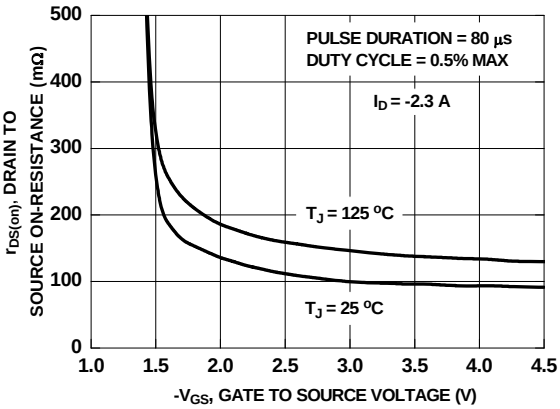


Figure 16. On-Resistance vs Gate to Source Voltage

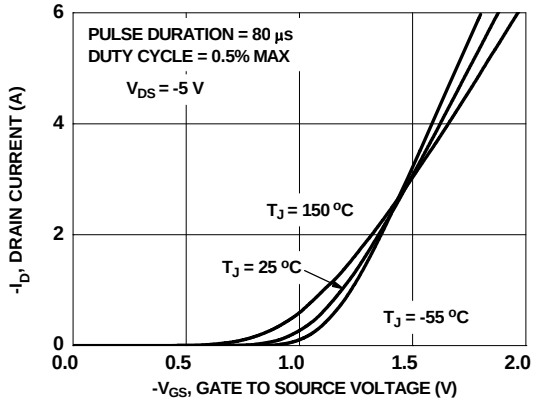


Figure 17. Transfer Characteristics

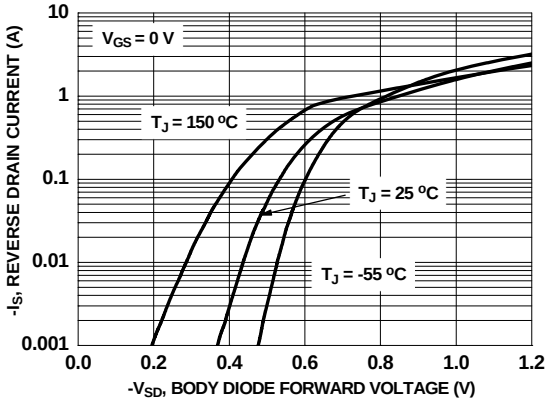


Figure 18. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics (Q2 P-Channel) T_J = 25°C unless otherwise noted

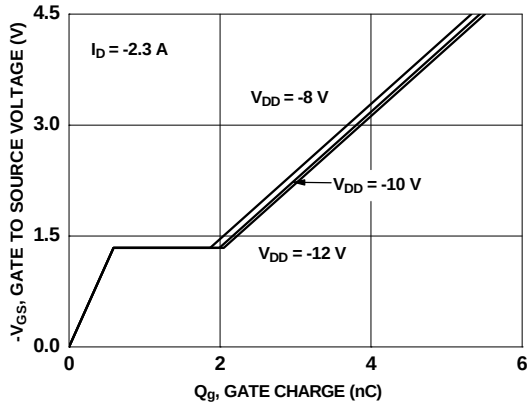


Figure 19. Gate Charge Characteristics

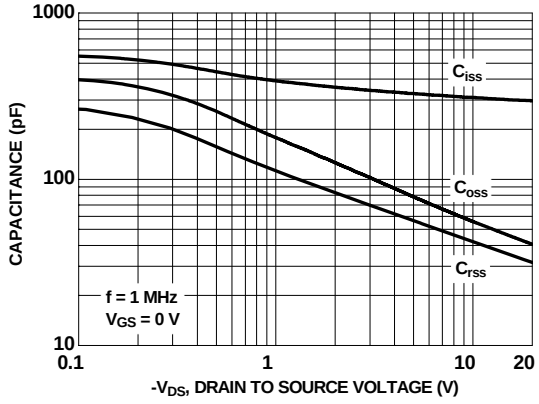


Figure 20. Capacitance vs Drain to Source Voltage

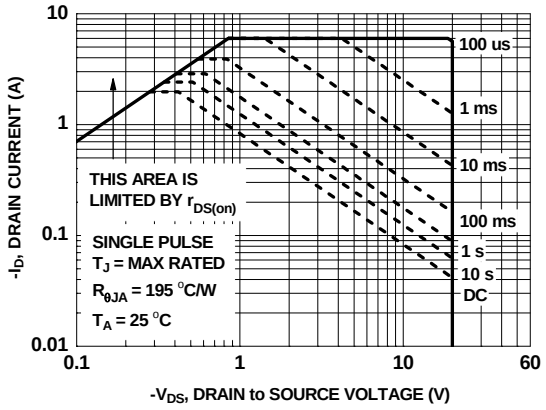


Figure 21. Forward Bias Safe Operating Area

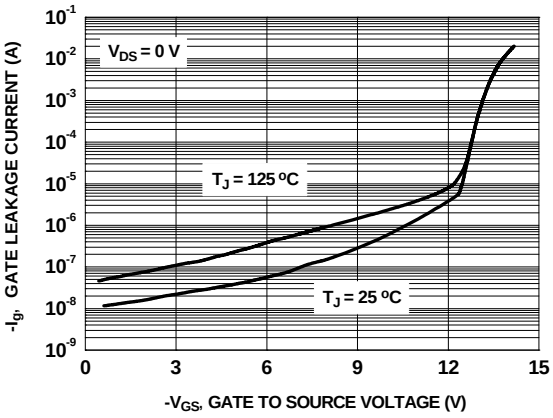


Figure 22. Gate Leakage Current vs Gate to Source Voltage

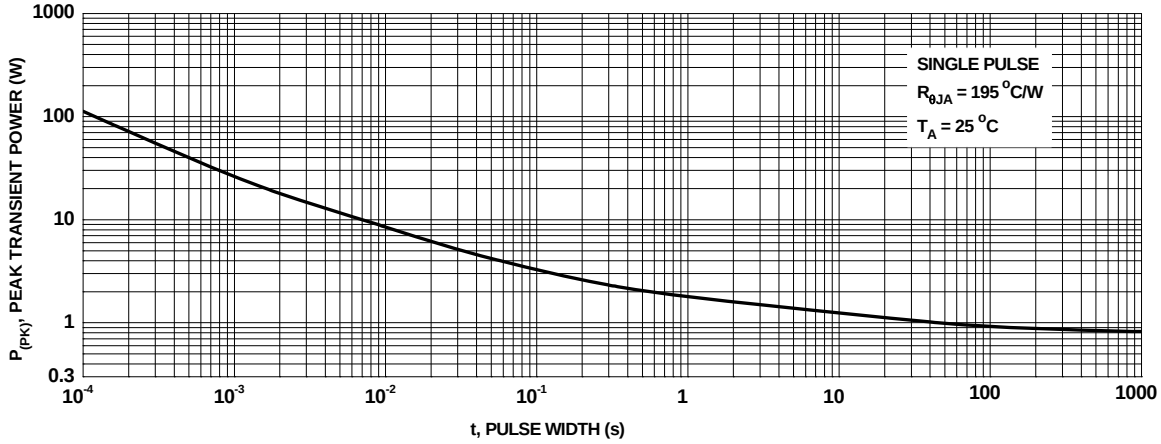


Fig 23. Single Pulse Maximum Power Dissipation

Typical Characteristics (Q2 P-Channel) T_J = 25 °C unless otherwise noted

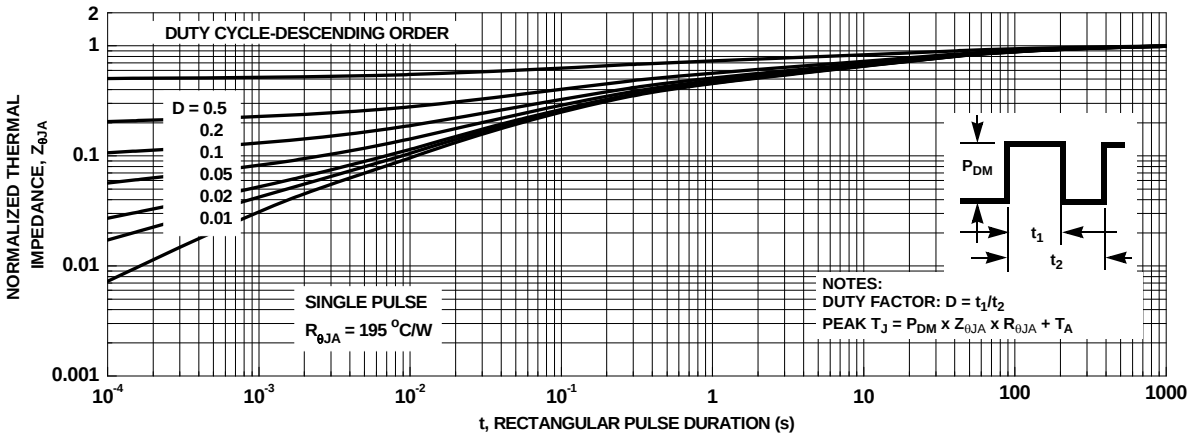
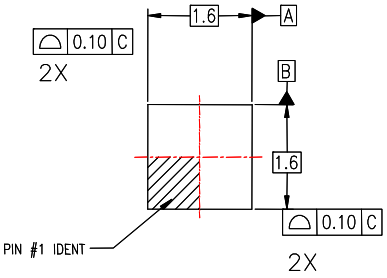
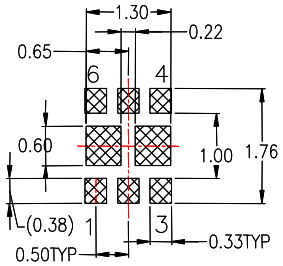


Figure 24. Junction-to-Ambient Transient Thermal Response Curve

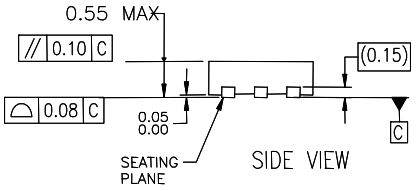
Dimensional Outline and Pad Layout



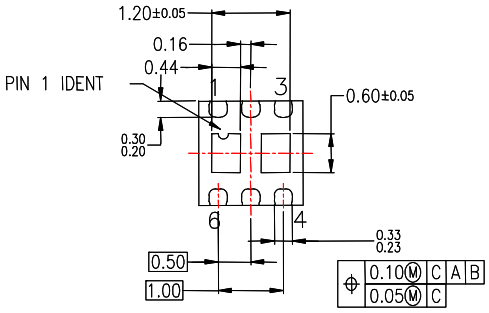
TOP VIEW



RECOMMENDED LAND PATTERN



SIDE VIEW



BOTTOM VIEW

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SupreMOS™
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1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
2. A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Fairchild's Anti-Counterfeiting Policy is also stated on our external website, www.Fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handing and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

PRODUCT STATUS DEFINITIONS
Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

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